







SN54LVC74A, SN74LVC74A

SCAS287V - JANUARY 1993 - REVISED MAY 2024

SNx4LVC74A Dual Positive-Edge-Triggered D-Type Flip-Flops With Clear and Preset

1 Features

- Operate from 1.65V to 3.6V
- Inputs accept voltages to 5.5V
- Maximum t_{pd} of 5.2ns at 3.3V
- Typical V_{OLP} (output ground bounce) < 0.8V at $V_{CC} = 3.3V$, $T_A = 25^{\circ}C$
- Typical V_{OHV} (output V_{OH} undershoot) >2V at $V_{CC} = 3.3V$, $T_A = 25$ °C
- Latch-up performance exceeds 250mA per JESD
- ESD protection exceeds JESD 22
 - 2000V human-body model (A114-A)
 - 1000V charged-device model (C101)

2 Applications

- Servers
- Medical, Healthcare, and Fitness
- Telecom Infrastructures
- TVs, Set-Top Boxes, and Audio
- Test and Measurement
- **Industrial Transport**
- Wireless Infrastructure
- Enterprise Switching
- **Motor Drives**
- **Factory Automation and Control**

3 Description

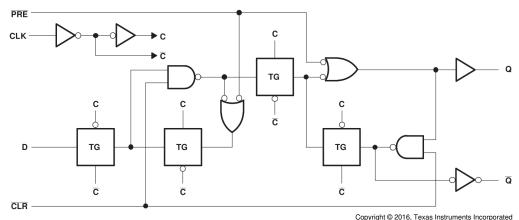
The SNx4LVC74A devices integrate two positive-edge triggered D-type flip-flops in one convenient device.

The SN54LVC74A is designed for 2.7V to 3.6V V_{CC} operation, and the SN74LVC74A is designed for 1.65V to 3.6V V_{CC} operation.

Device Information

Device information								
PART NUMBER	PACKAGE (1)	PACKAGE SIZE(2)	BODY SIZE(3)					
	BQA (WQFN, 14)	3mm × 2.5mm	3mm × 2.5mm					
	D (SOIC, 14)	8.65mm x 6mm	8.65mm × 3.91mm					
	DB (SSOP, 14)	6.2mm x 7.8mm	6.20mm × 5.30mm					
	NS (SOP, 14)	10.2mm x 7.8mm	10.20mm × 5.30mm					
SNx4LVC74A	PW (TSSOP, 14)	5mm x 6.4mm	5.00mm × 4.40mm					
	RGY (VQFN, 14)	3.50mm × 3.50mm	3.50mm × 3.50mm					
	J (CDIP, 14)	19.55mm x 7.9mm	19.56 mm × 6.67 mm					
	W (CFP, 14)	9.21mm x 9 mm	9.21 mm × 5.97 mm					
	FK (LCCC, 20)	8.9mm x 8.9mm	8.89 mm × 8.89 mm					

- For more information, see Mechanical, Packaging, and (1) Orderable Information.
- The package size (length × width) is a nominal value and includes pins, where applicable.
- The body size (length × width) is a nominal value and does not include pins.



Logic Diagram, Each Flip-Flop (Positive Logic)



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4 Pin Configuration and Functions

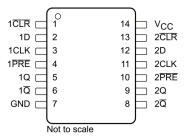


Figure 4-1. D, DB, J, PW, NS, or W Package 14-Pin SOIC, SSOP, CDIP, TSSOP, SO, or CFP (Top View)

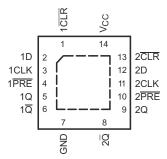


Figure 4-2. BQA or RGY Package 14-Pin WQFN or VQFN With Exposed Thermal Pad (Top View)

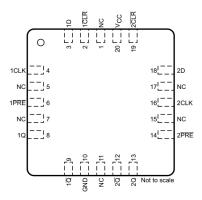


Figure 4-3. FK Package 20-Pin LCCC (Top View)

PIN I/O **DESCRIPTION** CDIP, CFP, PDIP, SO, SOIC, NAME LCCC SSOP, TSSOP, VQFN 1CLK 3 4 ı Channel 1 clock input 1 CLR 1 2 ı Channel 1 clear input. Pull low to set Q output low. 1D 2 Channel 1 data input 1 PRE 4 6 1 Channel 1 preset input. Pull low to set Q output high. 1Q 5 8 0 Channel 1 output 1 Q 6 9 0 Channel 1 inverted output 2CLK 11 16 ı Channel 2 clock input 2 CLR Channel 2 clear input. Pull low to set Q output low. 13 19 1 2D Channel 2 data input 12 18 1 2 PRE Channel 2 preset input. Pull low to set Q output high. 10 14 ı 2Q 9 Channel 2 output 13 0 2 Q 0 Channel 2 Inverted output 8 12 **GND** 7 10 Ground NC 1, 5, 7, 11, 15, 17 No connect V_{CC} 14 20 Supply

Table 4-1. Pin Functions



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
Supply voltage, V _{CC}		-0.5	6.5	V
Input voltage, V _I ⁽²⁾		-0.5	6.5	V
Output voltage, V _O ^{(2) (3)}		-0.5	V _{CC} + 0.5	V
Input clamp current, I _{IK}	V _I < 0		-50	mA
Output clamp current, I _{OK}	V _O < 0		-50	mA
Continuous output current, I _O	·		±50	mA
Continuous current through V _{CC} or GND			±100	mA
Storage temperature, T _{stg}		-65	150	°C

- (1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability
- (2) The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.
- (3) The value of V_{CC} is provided in *Recommended Operating Conditions*.

5.2 ESD Ratings

			VALUE	UNIT
\ <u></u>	V _(ESD) Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000	V
V _(ESD)		Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	±1000	V

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

see(1)

				MIN	MAX	UNIT
		Operating	SN54LVC74A	2	3.6	
V _{CC}	Supply voltage	Operating	SN74LVC74A	1.65	3.6	V
		Data retention only		1.5	3.6	
		V _{CC} = 1.65 V to 1.95 V	SN74LVC74A	0.65 × V _{CC}		
V _{IH}	High-level input voltage	V _{CC} = 2.3 V to 2.7 V	SN74LVC74A	1.7		V
		V _{CC} = 2.7 V to 3.6 V		2		
		V _{CC} = 1.65 V to 1.95 V	SN74LVC74A		0.35 × V _{CC}	
V _{IL}	Low-level input voltage	V _{CC} = 2.3 V to 2.7 V	SN74LVC74A		0.7	V
		V _{CC} = 2.7 V to 3.6 V			0.8	
VI	Input voltage			0	5.5	V
Vo	Output voltage			0	V _{CC}	V
		V _{CC} = 1.65 V	SN74LVC74A		-4	
	High lavel autout august	V _{CC} = 2.3 V	SN74LVC74A		-8	A
I _{OH}	High-level output current	V _{CC} = 2.7 V		74A 1.7 2 74A 0.35 × 74A 0 0 0 0 74A 74A	-12	mA
		V _{CC} = 3 V			-24	
		V _{CC} = 1.65 V	SN74LVC74A		4	
l	Laurelaurelauren errenak	V _{CC} = 2.3 V	SN74LVC74A		8	A
I _{OL}	Low-level output current	V _{CC} = 2.7 V	-		12	mA
		V _{CC} = 3 V			24	
Δt/Δv	Input transition rise or fall rate	-			10	ns/V

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5.3 Recommended Operating Conditions (continued)

see(1)

			MIN	MAX	UNIT
T. On another first sintenance true	SN54LVC74A	-55	125	°C	
I'A	Operating free-air temperature	SN74LVC74A	-40	125	

All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. See the TI application report, Implications of Slow or Floating CMOS Inputs (SCBA004).

5.4 Thermal Information: SN74LVC74A

				SN74I	LVC74A			
	THERMAL METRIC(1)	BQA (WQFN)	D (SOIC)	DB (SSOP)	NS (SO)	PW (TSSOP)	RGY (VQFN)	UNIT
		14 PINS	14 PINS	14 PINS	14 PINS	14 PINS	14 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	102.3	93.7	107.3	90.3	121.7	54.9	°C/W
R ₀ JC(top)	Junction-to-case (top) thermal resistance	96.8	54.8	59.2	48.1	50.3	52.2	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	70.9	48	54.6	49.1	63.4	30.8	°C/W
ΨЈТ	Junction-to-top characterization parameter	16.6	20.3	24.1	17.9	6.2	2.4	°C/W
ΨЈВ	Junction-to-board characterization parameter	70.9	47.7	54.1	48.8	62.8	30.9	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	50.1	_	_	_	_	12.5	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

5.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP MA	X UNIT
		I - 100 uA	V_{CC} = 1.65 V to 3.6 V and T_A = -55°C to 125°C (SN54LVC74A only)	V _{CC} - 0.2		
		I _{OH} = –100 μA	V_{CC} = 2.7 V to 3.6 V and T_A = -40°C to 125°C (SN74LVC74A only)	V _{CC} - 0.2		
V _{OH}	High-level output voltage			1.2		
011				1.7		
		= 12 mΛ	V _{CC} = 2.7 V	2.2		
		1 _{OH} = -12 mA	V _{CC} = 3 V	2.4		
		$I_{OH} = -24 \text{ mA}, V_{CC} = 3 \text{ V}$		2.2		
		I _{OL} = 100 μA	V_{CC} = 1.65 V to 3.6 V, and T_A = -40°C to 125°C (SN74LVC74A only)		0	2
			V _{CC} = 2.7 V to 3.6 V and T _A = -55°C to 125°C (SN54LVC74A only)		0	2
V _{OL}	Low-level output voltage		• • • • • • • • • • • • • • • • • • • •		0.4	5 V
					0	7
		$\begin{array}{c} V_{CC} = 2.7 \text{ V to } 3.6 \text{ V and } T_A = -40^{\circ}\text{C to} \\ 125^{\circ}\text{C (SN74LVC74A only)} \end{array} \qquad V_{CC} = 0.2 \\ \hline \\ I_{OH} = -4 \text{ mA, } V_{CC} = 1.65 \text{ V, and } T_A = -40^{\circ}\text{C to } 125^{\circ}\text{C} \\ \text{(SN74LVC74A only)} \end{array} \qquad \qquad 1.2 \\ \hline \\ I_{OH} = -8 \text{ mA, } V_{CC} = 2.3 \text{ V, and } T_A = -40^{\circ}\text{C to } 125^{\circ}\text{C} \\ \text{(SN74LVC74A only)} \end{array} \qquad \qquad \qquad 1.7 \\ \hline \\ I_{OH} = -12 \text{ mA} \qquad \qquad$	0	4		
		I _{OL} = 24 mA, V _{CC} =	3 V		0.2 0.45 0.7 0.4 0.55 ±5 10	5
I _I	Input current	$V_I = 5.5 \text{ V or GND},$	V _{CC} = 3.6 V		=	5 μΑ
I _{CC}	Supply current	$V_I = V_{CC}$ or GND, I_C	_D = 0, V _{CC} = 3.6 V		•	0 μΑ



5.5 Electrical Characteristics (continued)

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER TES		TEST CONDITIONS	MIN	TYP	MAX	UNIT
ΔI_{CC}	Change in supply current	One input at $V_{CC} = 0.6 \text{ V}$, other inputs at V_{CC} or GND, and $V_{CC} = 2.7 \text{ V}$ to 3.6 V			500	μΑ
Ci	Input capacitance	$V_1 = V_{CC}$ or GND, $V_{CC} = 3.3$ V, $T_A = 25$ °C		5		pF

5.6 Timing Requirements: SN54LVC74A

over recommended operating free-air temperature range (unless otherwise noted; see Parameter Measurement Information)

	-			MIN	MAX	UNIT
f	Clock fraguency	V _{CC} = 2.7 V			83	MHz
f _{clock}	V _{CC} = 2.7 V	100	IVII IZ			
t _w	Pulse duration	PRE or CLR low		3.3		ne
		CLK high or low		3.3		ns
	Data	Data	V _{CC} = 2.7 V	3.4		
	Satur time before CLKA		V _{CC} = 3.3 V ± 0.3 V	3		
t _{su}	Setup time before CLK	·	V _{CC} = 2.7 V	2.2		ns
		$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		2		
t _h	Hold time, data after CLK↑	•		1		ns

5.7 Timing Requirements: SN74LVC74A

over recommended operating free-air temperature range (unless otherwise noted; see Parameter Measurement Information)

		-		MIN	MAX	UNIT	
f _{clock}	Clock frequency	V _{CC} = 1.8 V or 2.5 V			83	MHz	
		PRE or CLR low	V _{CC} = 1.8 V ± 0.15 V	4.1			
t _w	Pulse duration	PRE OF CLR IOW	V _{CC} = 2.5 V ± 0.2 V	3.3		200	
			V _{CC} = 1.8 V ± 0.15 V	4.1		ns	
		CLK high or low	V _{CC} = 2.5 V ± 0.2 V	3.3			
			Data	V _{CC} = 1.8 V ± 0.15 V	3.6		
	Setup time before CLK↑	Data	V _{CC} = 2.5 V ± 0.2 V	2.3		200	
t _{su}	Setup time before CLK	DDE on CLD in a still	V _{CC} = 1.8 V ± 0.15 V	2.7		ns	
		PRE or CLR inactive	V _{CC} = 2.5 V ± 0.2 V	1.9			
t _h	Hold time, data after CLK↑	V _{CC} = 1.8 V or 2.5 V	<u> </u>	1		ns	

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5.8 Timing Requirements: SN74LVC74A, -40°C to 125°C and -40°C to 85°C

over recommended operating free-air temperature range (unless otherwise noted; see Parameter Measurement Information)

					MIN	MAX	UNIT
		T _A = -40°C to	V _{CC} = 2.7 V		83		
f_{clock}	Clock frequency	125°C	V _{CC} = 3.3 V ± 0.3 V			100	MHz
		$T_A = -40^{\circ}\text{C to } 85^{\circ}\text{C}$	and $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$			150	
	Dulco duration	PRE or CLR low	V _{CC} = 2.7 V or 3.3 V		3.3		no
t _w	Pulse duration	CLK high or low	V _{CC} = 2.7 V or 3.3 V	3.3		ns	
			T _Δ = -40°C to 125°C	V _{CC} = 2.7 V	3.4		
		Data	1A40 C to 125 C	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	3		
	Setup time before CLK↑		$T_A = -40$ °C to 85°C and	3		no	
t _{su}	Setup time before CLK		$T_{\Delta} = -40^{\circ}\text{C to } 125^{\circ}\text{C}$	V _{CC} = 2.7 V	2.2		ns
		PRE or CLR inactive	1 _A = -40 C to 125 C	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	2		
		madavo	$T_A = -40$ °C to 85°C and	2			
t _h	Hold time, data after CLK↑	V _{CC} = 2.7 V or 3.3 \	/	1		ns	

5.9 Switching Characteristics: SN54LVC74A

over recommended operating free-air temperature range (unless otherwise noted; see Parameter Measurement Information)

	PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	MAX	UNIT	
f _{max}	Maximum clock			V _{CC} = 2.7 V	83		MHz	
	frequency	_	_	V _{CC} = 3.3 V ± 0.3 V	100			
		OLIV.		V _{CC} = 2.7 V		6		
	Propagation (delay)	CLK		V _{CC} = 2.7 V	1	5.2		
t _{pd}	time		Q or Q	V _{CC} = 3.3 V ± 0.3 V		6.4	ns	
		PRE or CLR		V _{CC} = 3.3 V ± 0.3 V	1	5.4		

5.10 Switching Characteristics: SN74LVC74A

over recommended operating free-air temperature range (unless otherwise noted; see Parameter Measurement Information)

	PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	MAX	UNIT
f _{max}	Maximum clock frequency	_	_		83		MHz
		CLK PRE		V _{CC} = 1.8 V ± 0.15 V	1	7.1	
	Propagation (delay)		Q or Q	V _{CC} = 2.5 V ± 0.2 V	1	4.4	ns
t _{pd}	time		QUIQ	V _{CC} = 1.8 V ± 0.15 V	1	6.9	
		or CLR		V _{CC} = 2.5 V ± 0.2 V	1	4.6	



5.11 Switching Characteristics: SN74LVC74A, -40°C to 125°C and -40°C to 85°C

over recommended operating free-air temperature range (unless otherwise noted; see Parameter Measurement Information)

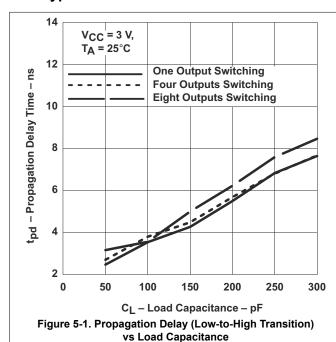
	PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CO	TEST CONDITIONS			
				T _Δ = -40°C to 125°C	V _{CC} = 2.7 V	83		
f _{max}	Maximum clock frequency	_	_	1 _A = -40 C to 125 C	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	100		MHz
	nequency			$T_A = -40^{\circ}\text{C} \text{ to } 85^{\circ}\text{C} \text{ and}$	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	150		
		CLK y)		T _Δ = –40°C to 125°C	V _{CC} = 2.7 V	1	6	
			Q or Q	1A40 C to 123 C	V _{CC} = 3.3 V ± 0.3 V		5.2	
	Propagation (delay)			$T_A = -40$ °C to 85°C and	V _{CC} = 3.3 V ± 0.3 V	1	5.2	no
t _{pd}	time			$T_{\Delta} = -40^{\circ}\text{C to } 125^{\circ}\text{C}$	V _{CC} = 2.7 V	1	6.4	ns
		PRE or CLR		1A = -40 C to 125 C	V _{CC} = 3.3 V ± 0.3 V		5.4	
				$T_A = -40$ °C to 85°C and	1	5.4		
t _{sk(o)}	Skew (time), output	_	_	$T_A = -40$ °C to 85°C and	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		1	ns

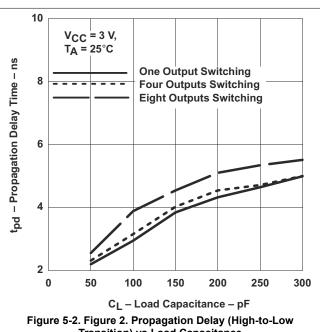
5.12 Operating Characteristics

 $T_A = 25^{\circ}C$

	PARAMETER	TEST C	TYP	UNIT	
			V _{CC} = 1.8 V	24	
C _{pd}	Power dissipation capacitance per flip-flop	f = 10 MHz	V _{CC} = 2.5 V	24	pF
			V _{CC} = 3.3 V	26	

5.13 Typical Characteristics





Transition) vs Load Capacitance

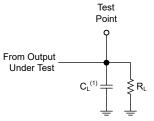


6 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily for the examples listed in the following table. All input pulses are supplied by generators having the following characteristics: PRR \leq 1MHz, $Z_O = 50\Omega$, $t_t \leq$ 2.5ns.

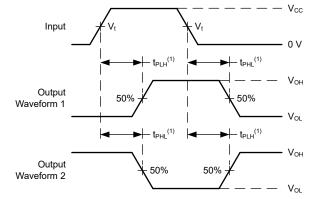
The outputs are measured individually with one input transition per measurement.

V _{cc}	V _t	R _L	CL	ΔV
1.8V ± 0.15V	V _{CC} /2	1kΩ	30pF	0.15V
2.5V ± 0.2V	V _{CC} /2	500Ω	30pF	0.15V
2.7V	1.5V	500Ω	50pF	0.3V
3.3V ± 0.3V	1.5V	500Ω	50pF	0.3V



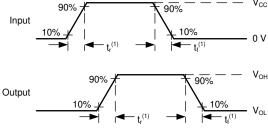
(1) C_L includes probe and test-fixture capacitance.

Figure 6-1. Load Circuit for Push-Pull Outputs



(1) The greater between t_{PLH} and t_{PHL} is the same as t_{pd} .

Figure 6-2. Voltage Waveforms Propagation Delays



(1) The greater between t_r and t_f is the same as t_t .

Figure 6-3. Voltage Waveforms, Input and Output Transition Times

7 Detailed Description

7.1 Overview

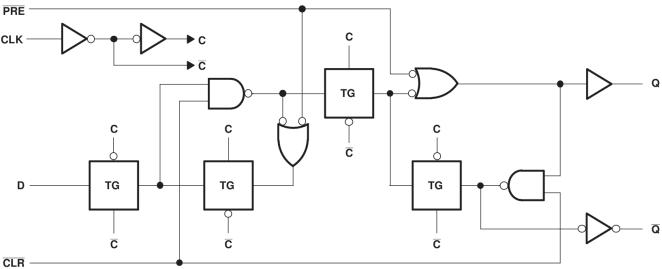
The SNx4LVC74A devices feature two independent positive-edge triggered D flip-flops. Integrated preset (PRE) and clear (CLR) functions allow for easy setup and control during operation.

The SN54LVC74A device is specified from -55°C to 125°C, and the SN74LVC74A device is specified from -40°C to 125°C.

A low level at the preset (\overline{PRE}) or clear (\overline{CLR}) inputs sets or resets the outputs, regardless of the levels of the other inputs. When \overline{PRE} and \overline{CLR} are inactive (high), data at the data (D) input meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

The data I/Os and control inputs are overvoltage tolerant. This feature allows the use of these devices for down-translation in a mixed-voltage environment.

7.2 Functional Block Diagram



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7.3 Feature Description

A low level at the preset (\overline{PRE}) or clear (\overline{CLR}) inputs sets or resets the outputs, regardless of the levels of the other inputs. When \overline{PRE} and \overline{CLR} are inactive (high), data at the data (D) input meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

7.4 Device Functional Modes

Table 7-1 describes the SNx4LVC74A functionality and interactions between the PRE, CLR, CLK, and D inputs.

Table 7-1. Function Table **INPUTS OUTPUTS** PRE **CLR CLK** D Q $\overline{\mathbf{Q}}$ L Н Χ Х Н L Н L Χ Χ L Н L L Х Х $H^{(1)}$ $H^{(1)}$ Н Н Н Н L 1

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	ub.0 /			ocaoc	•,
	INP	OUTPUTS			
PRE	CLR	CLK	D	Q	Q
Н	Н	1	L	L	Н
н	н	ı	×	Oo	<u> </u>

Table 7-1. Function Table (continued)

8 Application and Implementation

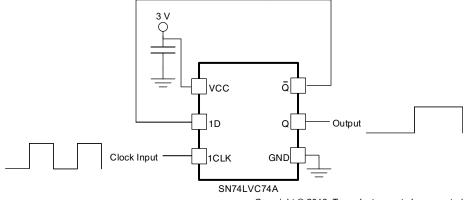
Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

8.1 Application Information

A common application for the SN74LVC74A is a frequency divider. By connecting the $\overline{\mathbb{Q}}$ output to the D input, the Q output toggles states on each positive edge of the incoming clock signal. Because it takes two positive edges, or two clock pulses, to complete one complete pulse on the output (one pulse to toggle from low to high, another to toggle from high to low), the incoming clock frequency is effectively divided by two.

8.2 Typical Application



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Figure 8-1. Frequency Divider

8.2.1 Design Requirements

This device uses CMOS technology and has balanced output drive. Avoid bus contention because it can drive currents in excess of maximum limits. The high drive also creates fast edges into light loads, so consider routing and load conditions to prevent ringing.

8.2.2 Detailed Design Procedure

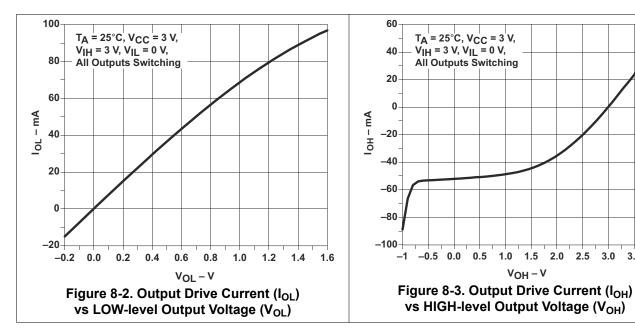
- 1. Recommended input conditions:
 - For rise time and fall time specification, see ($\Delta t/\Delta V$) in *Recommended Operating Conditions*.
 - For specified high and low levels, see (V_{IH} and V_{IL}) in Recommended Operating Conditions.
 - Inputs are overvoltage tolerant allowing them to go as high as (V_I max) in Recommended Operating
 Conditions at any valid V_{CC}.
- 2. Recommended maximum output conditions:

⁽¹⁾ This configuration is nonstable; that is, it does not persist when PRE or CLR returns to its inactive (high) level.



- Load currents must not exceed (I_O max) per output and must not exceed (Continuous current through V_{CC} or GND) total current for the part. These limits are located in *Absolute Maximum Ratings*.
- Outputs must not be pulled above V_{CC}.

8.2.3 Application Curves



8.3 Power Supply Recommendations

The power supply may be any voltage between the minimum and maximum supply voltage rating located in *Recommended Operating Conditions*.

Each V_{CC} terminal must have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for devices with a single supply. If there are multiple V_{CC} terminals, then 0.01- μ F or 0.022- μ F capacitors are recommended for each power terminal. It is permissible to parallel multiple bypass capacitors to reject different frequencies of noise. Multiple bypass capacitors may be paralleled to reject different frequencies of noise. The bypass capacitor must be installed as close to the power terminal as possible for the best results.

8.4 Layout

8.4.1 Layout Guidelines

Inputs must not float when using multiple bit logic devices. In many cases, functions or parts of functions of digital logic devices are unused. Some examples include situations when only two inputs of a triple-input AND gate are used, or when only 3 of the 4-buffer gates are used. Such input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states.

Specified in Figure 8-4 are rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, they are tied to GND or V_{CC} , whichever makes more sense or is more convenient.



8.4.2 Layout Example

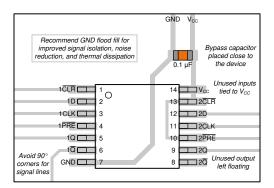


Figure 8-4. Layout Diagram



9 Device and Documentation Support

9.1 Documentation Support

9.1.1 Related Documentation

For related documentation see the following:

Implications of Slow or Floating CMOS Inputs (SCBA004)

9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

9.4 Trademarks

TI E2E[™] is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

C	hanges from Revision U (January 2017) to Revision V (May 2024)	Page
•	Updated the numbering format for tables, figures, and cross-references throughout the document	1
•	Added BQA package to Device Information table, Pin Configuration and Functions section, and Therr Information table	
•	Added package size to Device Information table	1
С	hanges from Revision T (July 2013) to Revision U (January 2017)	Page
C		Page
<u>С</u>	hanges from Revision T (July 2013) to Revision U (January 2017) Added ESD Ratings table, Feature Description section, Device Functional Modes, Application and Implementation section, Power Supply Recommendations section, Layout section, Device and	Page
C	Added ESD Ratings table, Feature Description section, Device Functional Modes, Application and	
<u>C</u>	Added ESD Ratings table, Feature Description section, Device Functional Modes, Application and Implementation section, Power Supply Recommendations section, Layout section, Device and	1

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11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
5962-9761601Q2A	ACTIVE	LCCC	FK	20	55	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962- 9761601Q2A SNJ54LVC 74AFK	Samples
5962-9761601QCA	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9761601QC A SNJ54LVC74AJ	Samples
5962-9761601QDA	ACTIVE	CFP	W	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9761601QD A SNJ54LVC74AW	Samples
5962-9761601VDA	ACTIVE	CFP	W	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9761601VD A SNV54LVC74AW	Samples
SN74LVC74ABQAR	ACTIVE	WQFN	BQA	14	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LVC74A	Samples
SN74LVC74AD	ACTIVE	SOIC	D	14	50	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LVC74A	Samples
SN74LVC74ADBR	ACTIVE	SSOP	DB	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LC74A	Samples
SN74LVC74ADBRG4	ACTIVE	SSOP	DB	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LC74A	Samples
SN74LVC74ADR	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LVC74A	Samples
SN74LVC74ADRE4	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LVC74A	Samples
SN74LVC74ADT	ACTIVE	SOIC	D	14	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LVC74A	Samples
SN74LVC74ANSR	ACTIVE	SO	NS	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LVC74A	Samples
SN74LVC74APW	ACTIVE	TSSOP	PW	14	90	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LC74A	Samples
SN74LVC74APWG4	ACTIVE	TSSOP	PW	14	90	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LC74A	Samples
SN74LVC74APWR	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 125	LC74A	Samples
SN74LVC74APWRE4	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LC74A	Samples
SN74LVC74APWRG4	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LC74A	Samples



www.ti.com 16-Jun-2024

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN74LVC74APWT	ACTIVE	TSSOP	PW	14	250	RoHS & Green	(6) NIPDAU	Level-1-260C-UNLIM	-40 to 125	LC74A	Samples
SN74LVC74APWTG4	ACTIVE	TSSOP	PW	14	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LC74A	Samples
SN74LVC74ARGYR	ACTIVE	VQFN	RGY	14	3000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	LC74A	Samples
SNJ54LVC74AFK	ACTIVE	LCCC	FK	20	55	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962- 9761601Q2A SNJ54LVC 74AFK	Samples
SNJ54LVC74AJ	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9761601QC A SNJ54LVC74AJ	Samples
SNJ54LVC74AW	ACTIVE	CFP	W	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9761601QD A SNJ54LVC74AW	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

PACKAGE OPTION ADDENDUM

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(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN54LVC74A, SN54LVC74A-SP, SN74LVC74A:

Catalog: SN74LVC74A, SN54LVC74A

Automotive: SN74LVC74A-Q1, SN74LVC74A-Q1

● Enhanced Product: SN74LVC74A-EP, SN74LVC74A-EP

Military: SN54LVC74A

Space: SN54LVC74A-SP

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Enhanced Product Supports Defense, Aerospace and Medical Applications
- Military QML certified for Military and Defense Applications
- Space Radiation tolerant, ceramic packaging and qualified for use in Space-based application



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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74LVC74ABQAR	WQFN	BQA	14	3000	180.0	12.4	2.8	3.3	1.1	4.0	12.0	Q1
SN74LVC74ADBR	SSOP	DB	14	2000	330.0	16.4	8.35	6.6	2.4	12.0	16.0	Q1
SN74LVC74ADR	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
SN74LVC74ADT	SOIC	D	14	250	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
SN74LVC74ANSR	so	NS	14	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
SN74LVC74APWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74LVC74APWRG4	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74LVC74APWT	TSSOP	PW	14	250	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74LVC74ARGYR	VQFN	RGY	14	3000	330.0	12.4	3.75	3.75	1.15	8.0	12.0	Q1



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*All dimensions are nominal

7 III dimensions are nominal							
Device	Package Type	Package Drawing	Pins	SPQ Length (mm)		Width (mm)	Height (mm)
SN74LVC74ABQAR	WQFN	BQA	14	3000	210.0	185.0	35.0
SN74LVC74ADBR	SSOP	DB	14	2000	356.0	356.0	35.0
SN74LVC74ADR	SOIC	D	14	2500	356.0	356.0	35.0
SN74LVC74ADT	SOIC	D	14	250	210.0	185.0	35.0
SN74LVC74ANSR	SO	NS	14	2000	356.0	356.0	35.0
SN74LVC74APWR	TSSOP	PW	14	2000	356.0	356.0	35.0
SN74LVC74APWRG4	TSSOP	PW	14	2000	356.0	356.0	35.0
SN74LVC74APWT	TSSOP	PW	14	250	356.0	356.0	35.0
SN74LVC74ARGYR	VQFN	RGY	14	3000	356.0	356.0	35.0

PACKAGE MATERIALS INFORMATION

www.ti.com 25-Sep-2024

TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
5962-9761601Q2A	FK	LCCC	20	55	506.98	12.06	2030	NA
5962-9761601VDA	W	CFP	14	25	506.98	26.16	6220	NA
SN74LVC74AD	D	SOIC	14	50	506.6	8	3940	4.32
SN74LVC74APW	PW	TSSOP	14	90	530	10.2	3600	3.5
SN74LVC74APWG4	PW	TSSOP	14	90	530	10.2	3600	3.5
SNJ54LVC74AFK	FK	LCCC	20	55	506.98	12.06	2030	NA



SMALL OUTLINE INTEGRATED CIRCUIT



- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
- 5. Reference JEDEC registration MS-012, variation AB.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) package configuration.
- D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- Pin 1 identifiers are located on both top and bottom of the package and within the zone indicated. The Pin 1 identifiers are either a molded, marked, or metal feature.
- G. Package complies to JEDEC MO-241 variation BA.



RGY (S-PVQFN-N14)

PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No—Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

Exposed Thermal Pad Dimensions

4206353-2/P 03/14

NOTE: All linear dimensions are in millimeters



RGY (S-PVQFN-N14)

PLASTIC QUAD FLATPACK NO-LEAD



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat—Pack QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com http://www.ti.com.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.



2.5 x 3, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



INSTRUMENTS www.ti.com

PLASTIC QUAD FLAT PACK-NO LEAD



- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



PLASTIC QUAD FLAT PACK-NO LEAD



NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLAT PACK-NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

MECHANICAL DATA

NS (R-PDSO-G**)

14-PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



W (R-GDFP-F14)

CERAMIC DUAL FLATPACK



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only.
- E. Falls within MIL STD 1835 GDFP1-F14







- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
 4. Reference JEDEC registration MO-150.





NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



8.89 x 8.89, 1.27 mm pitch

LEADLESS CERAMIC CHIP CARRIER

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



CERAMIC DUAL IN LINE PACKAGE



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4040083-5/G





CERAMIC DUAL IN LINE PACKAGE



- 1. All controlling linear dimensions are in inches. Dimensions in brackets are in millimeters. Any dimension in brackets or parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This package is hermitically sealed with a ceramic lid using glass frit.
- His package is remitted by sealed with a ceramic its using glass mit.
 Index point is provided on cap for terminal identification only and on press ceramic glass frit seal only.
 Falls within MIL-STD-1835 and GDIP1-T14.



CERAMIC DUAL IN LINE PACKAGE







- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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